

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecg.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002-01 CB Certificate No.: JQAQ0002-002-T

Schedule Number: IECQ-L JQAJP 13.0002-01-S

Rev No.: 4

Revision Date: 2016/01/22

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TESTD PARTS

Fixed capacitor, Fixed resister, Potentiometer, Varistor, Thermistor, Connector, Relay, Switch, Printed circuit board, Semiconductor Devices, Semiconductor Integrated Circuit and Optical Component

ENVIRONMENTAL TEST

IEC 60068-2-1:2013	Cold
IEC 60068-2-2:2007	Dry heat
IEC 60068-2-11:1981	Salt mist
IEC 60068-2-14:2009	Change of temperature
IEC 60068-2-18:2000	Test R and guidance: Water
IEC 60068-2-30:2005	Damp heat, cyclic (12+12-hour cycle)
IEC 60068-2-38:2009	Composite temperature/humidity cyclic test
JIS C 60068-2-42:1993	Sulphur dioxide test for contacts and connections
JIS C 60068-2-43:1993	Hydrogen sulphide test for contacts and connections
IEC 60068-2-52:1996	Salt mist, cyclic (sodium chloride solution)
IEC 60068-2-60:1995	Flowing mixed gas corrosion test
IEC 60068-2-66:1994	Damp heat, steady state (unsaturated pressurized vapour)
IEC 60068-2-68:1998	Dust and sand
IEC 60068-2-78:2012	Damp heat, steady state
JIS D 0205:1987	Test method of weatherability for automotive parts
JASO D 014-4:2014	Road vehicles - Environmental conditions and testing for
	electrical and electronic equipment - Part 4: Climatic loads
ISO 20653:2013	Road vehicles - Degrees of protection (IP code) - Protection of
	electrical equipment against foreign objects, water and access
MIL STD 202G	Test method standard electronic and electrical component parts
MIL STD 883J	Test method standard microcircuts

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MECHANICAL TEST

IEC 60068-2-6:2007 Vibration (sinusoidal)

IEC 60068-2-27:2008 Shock

IEC 60068-2-31:2008 Rough handling shocks, primarily for

equipment-type specimens

IEC 60068-2-53:2010 Tests and Guidance: Combined climatic (temperature/humidity)

and dynamic (vibration/shock) tests

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